INFORMATION DISCLOSURE CITATION PTO-1449 Submitted: July 3, 2003				Atty Docket: 061450/0304608 FID-101-D4		Serial No. to be assigned		
				Applicant: S. Prakash				
				Filing Date: Herewith		Prior Group Art Unit: 2856		
411		译作 Wish	PATENT	APPLICATIONS A			Į j	
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME		CLASS	SUBCLASS	FILING	DATE
RR	5,723,981	03 Mar 1998	Hellemans et al.		324	719	06/25/	96
R	5,992,226	11/1999	Green et al.		73	105		
RP	5,763,768	06/1998	Henderson, et al.		73	105		
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EXAMINER'S INITIALS	PATENT NO.	DATE		COUNTRY	CLAS	SUBCLASS	Trans	lation
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	L SALOTHERIDOC	UMENTS (inc	ı lüding/At	thor, fitte Date Pertii	ientlRag	S.Etc.)		
O P	De Wolf, et al. "Lateral and vertical dopant profiling in semiconductors by atomic force microscopy using							
RR	conducting tops" (J. Vac. Sci. Tech. A 13(3), May/June 1995, pp. 1699-1704							
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EXAMINER RAEVIS				DATE CONSIDERED 3-24 - 04				

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.